

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/770,876	BLUNK ET AL.	BLUNK ET AL.	
Examiner	Art Unit	Art Unit	
Dah-Wei D. Yuan	1745	1745	

	SEARCHED				
Class	Subclass	Date	Examiner		
429	12	5/23/2007	DWY		
429	34	5/23/2007	DWY		
429	44	5/23/2007	DWY		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH	ES Strategy)
	DATE	EXMR
EAST	5/23/2007	DWY
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